

Search Notes

Application/Control No.

10/756,776

Examiner

Phillip Nguyen

Applicant(s)/Patent under
Reexamination

TANAKA, KOICHIRO

Art Unit

2828

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST text search (see the printout)	8/19/2006	PN